The 8th International Conference on Microelectronics and Plasma Technology | The 9th International Symposium on Functional Materials

Joint International Conference on The 8th ICMAP & The 9th ISFM

January 17-20, 2021 | Online Conference

| [WB1] Plasma Diagnostics and Process Monitoring Technology II | | | | |
|---|---|--|--|--|
| Date / Time | January 20 (Wed.), 2021 / 09:00-10:10 | | | |
| Place | Channel B | | | |
| Session Chair(s) | Se Youn Moon (Jeonbuk Nat'l Univ., Korea) | | | |

[WB1-1] Invited

Solutions to the Challenges of Quantitative Neutral Species Measurements in Process Plasmas Jianping Zhao¹, Peter Ventzek¹, Charles Schlechte¹, John Carroll¹, Michael Hummel¹, Toshihiko Iwao², and Kiyotaka Ishibashi² ¹TEL, USA, ²TEL, Japan

[WB1-2]

Investigation of Power Coupling Property in E-H Mode Integrated Inductively Coupled Plasmas Haneul Lee, Ingyu Lee, Sung Hyun Son, Jaemin Song, and Gon-Ho Kim Seoul Nat'l Univ., Korea

| [WB1-3] | 0 | 9:50-10:10 | | | | |
|---|----|------------|------|------------|--|--|
| Computational Analyses of TEOS-Based Plasma Characteristics | to | Clarify | SiO₂ | Deposition | | |
| Mechanisms in PECVD Processes | | | | | | |

Hu Li and Kazuki Denpoh Tokyo Electron Tech. Solutions, Japan

09:30-09:50

09:00-09:30